

**Search Notes**

Application/Control No.

10/667,249

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under  
Reexamination

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Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	149.ccls. and table and (pre near1 distort\$3)	06/01/06	NKV
375	296.ccls. and table and (pre near1 distort\$3)	06/01/06	NKV
375	297.ccls. and table and (pre near1 distort\$3)	06/01/06	NKV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR